

CSD18504Q5A

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40V N-Channel NexFET[™] Power MOSFETs

Check for Samples: CSD18504Q5A

FEATURES

- Ultra Low Qg and Qgd
- Low Thermal Resistance
- Avalanche Rated
- Logic Level
- Pb Free Terminal Plating
- RoHS Compliant
- Halogen Free
- SON 5-mm × 6-mm Plastic Package

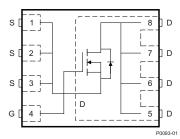
APPLICATIONS

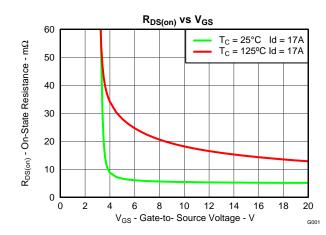
- DC-DC Conversion
- Secondary Side Synchronous Rectifier
- Battery Motor Control

DESCRIPTION

The NexFET[™] power MOSFET has been designed to minimize losses in power conversion applications.

Figure 1. Top View





PRODUCT SUMMARY

	/alues at 25ºC therwise stated	TYPICAL VA	UNIT	
V _{DS}	Drain to Source Voltage 40			
Qg	Gate Charge Total (4.5V)	7.7	nC	
Q _{gd}	Gate Charge Gate to Drain	2.4	nC	
Р	Drain to Source On Resistance	$V_{GS} = 4.5V$	7.5	mΩ
R _{DS(on)}	Drain to Source On Resistance	V _{GS} = 10V 5.3		mΩ
V _{GS(th)}	Threshold Voltage	1.9	V	

ORDERING INFORMATION

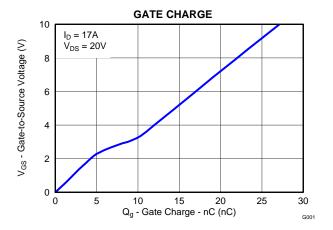
Device	vice Package		Qty	Ship
CSD18504Q5A	SON 5-mm × 6-mm Plastic Package	13-Inch Reel	2500	Tape and Reel

ABSOLUTE MAXIMUM RATINGS

$T_A = 2$	5°C unless otherwise stated	VALUE	UNIT	
V_{DS}	Drain to Source Voltage	40	V	
V_{GS}	Gate to Source Voltage	±20	V	
	Continuous Drain Current (Package limited), $T_C = 25^{\circ}C$	50		
I _D	Continuous Drain Current (Silicon limited), $T_C = 25^{\circ}C$	75	A	
	Continuous Drain Current, $T_A = 25^{\circ}C^{(1)}$	15		
I _{DM}	Pulsed Drain Current, $T_A = 25^{\circ}C^{(2)}$	95	А	
PD	Power Dissipation ⁽¹⁾	3.1	W	
T _J , T _{STG}	Operating Junction and Storage Temperature Range	-55 to 150	°C	
E _{AS}	Avalanche Energy, single pulse $I_D = 43A$, L = 0.1mH, $R_G = 25\Omega$	92	mJ	

(1) Typical $R_{\theta JA}$ = 41°C/W on a 1-inch² , 2-oz. Cu pad on a 0.06-inch thick FR4 PCB.

(2) Pulse duration \leq 300µs, duty cycle \leq 2%



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of the Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters. SLPS366-JUNE 2012

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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

ELECTRICAL CHARACTERISTICS

$(T_A = 25^{\circ}C \text{ unless otherwise stated})$

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
Static C	haracteristics	· ·		ľ	
BV _{DSS}	Drain to Source Voltage	$V_{GS} = 0V, I_D = 250\mu A$	40		V
I _{DSS}	Drain to Source Leakage Current	$V_{GS} = 0V, V_{DS} = 32V$		1	μA
I _{GSS}	Gate to Source Leakage Current	$V_{DS} = 0V, V_{GS} = 20V$		100	nA
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.5 1.9	2.4	V
D	Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 17A$	7.5	9.8	mΩ
R _{DS(on)}	Drain to Source On Resistance	$V_{GS} = 10V, I_D = 17A$	5.3	6.6	mΩ
9 _{fs}	Transconductance	$V_{DS} = 20V, I_{D} = 17A$	63		S
Dynamic	c Characteristics				
C _{iss}	Input Capacitance		1380	1656	pF
Coss	Output Capacitance	$V_{GS} = 0V$, $V_{DS} = 20V$, $f = 1MHz$	310	372	pF
C _{rss}	Reverse Transfer Capacitance		8	9.6	pF
R_{G}	Series Gate Resistance		1.4	2.8	Ω
Qg	Gate Charge Total (4.5V)		7.7	9.2	nC
Qg	Gate Charge Total (10V)		16	19	
Q _{gd}	Gate Charge Gate to Drain	$V_{DS} = 20V, I_D = 17A$	2.4		nC
Q _{gs}	Gate Charge Gate to Source		3.2		nC
Q _{g(th)}	Gate Charge at Vth		2.2		nC
Q _{oss}	Output Charge	$V_{DS} = 20V, V_{GS} = 0V$	21		nC
t _{d(on)}	Turn On Delay Time		3.2		ns
t _r	Rise Time	V _{DS} = 20V, V _{GS} = 10V,	6.8		ns
t _{d(off)}	Turn Off Delay Time	$I_{DS} = 17A, R_G = 2\Omega$	12		ns
t _f	Fall Time		2		ns
Diode C	haracteristics				
V_{SD}	Diode Forward Voltage	$I_{SD} = 17A, V_{GS} = 0V$	0.8	1	V
Q _{rr}	Reverse Recovery Charge	V _{DS} = 20V, I _F = 17A,	18		nC
t _{rr}	Reverse Recovery Time	di/dt = 300A/µs	28		ns

THERMAL CHARACTERISTICS

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$

	PARAMETER	MIN	TYP	MAX	UNIT
$R_{ extsf{ heta}JC}$	Thermal Resistance Junction to Case ⁽¹⁾			2	°C/W
R_{\thetaJA}	Thermal Resistance Junction to Ambient ⁽¹⁾⁽²⁾			51	°C/W

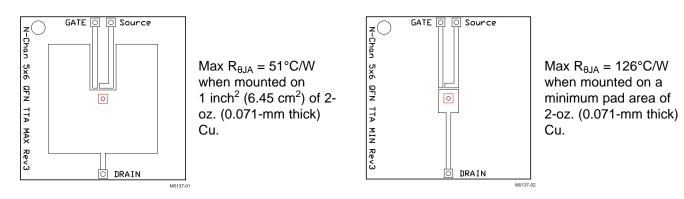
 $R_{ ext{BJC}}$ is determined with the device mounted on a 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu pad on a 1.5-inch x 1.5-inch (3.81-cm x 3.81-cm), 0.06-inch (1.52-mm) thick FR4 PCB. $R_{ ext{BJC}}$ is specified by design, whereas $R_{ ext{BJA}}$ is determined by the user's board design. Device mounted on FR4 material with 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu. (1)

(2)



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TYPICAL MOSFET CHARACTERISTICS

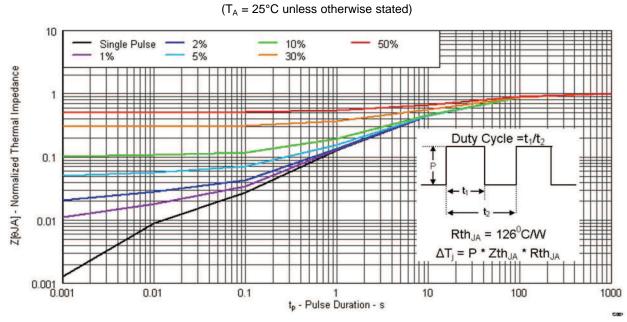
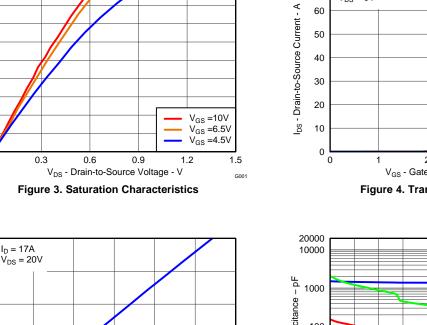
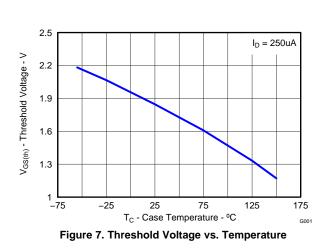


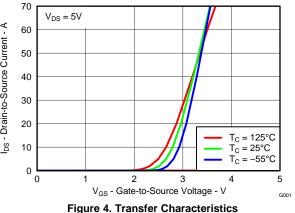
Figure 2. Transient Thermal Impedance

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TYPICAL MOSFET CHARACTERISTICS (continued)







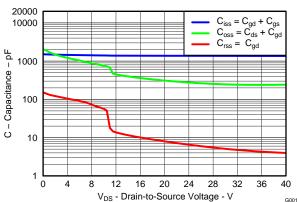


Figure 6. Capacitance

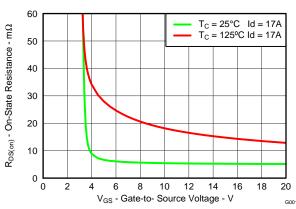


Figure 8. On-State Resistance vs. Gate-to-Source Voltage



Q_a - Gate Charge - nC (nC)

Figure 5. Gate Charge

G001

V_{GS} - Gate-to-Source Voltage (V)

I_{DS} - Drain-to-Source Current - A

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TYPICAL MOSFET CHARACTERISTICS (continued)

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$

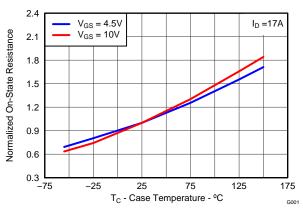
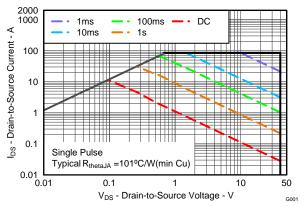
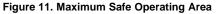
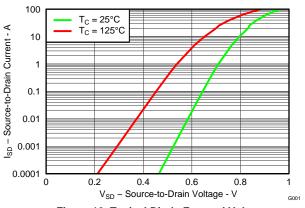


Figure 9. Normalized On-State Resistance vs. Temperature









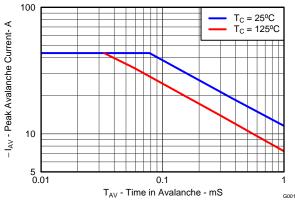
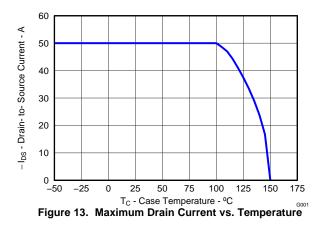


Figure 12. Single Pulse Unclamped Inductive Switching

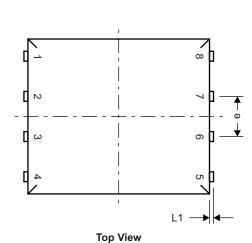


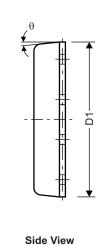
TEXAS INSTRUMENTS

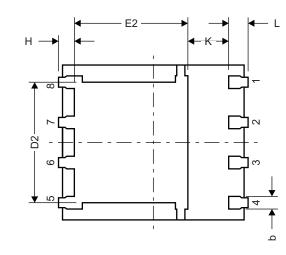
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MECHANICAL DATA

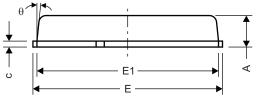
Q5A Package Dimensions







Bottom View



Front View

M0135-01

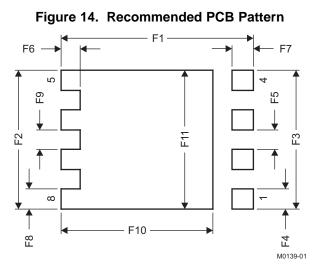
DIM		MILLIMETERS	
DIM	MIN	NOM	MAX
A	0.90	1.00	1.10
b	0.33	0.41	0.51
С	0.20	0.25	0.34
D1	4.80	4.90	5.00
D2	3.61	3.81	4.02
E	5.90	6.00	6.10
E1	5.70	5.75	5.80
E2	3.38	3.58	3.78
е	1.17	1.27	1.37
Н	0.41	0.56	0.71
К	1.10		
L	0.51	0.61	0.71
L1	0.06	0.13	0.20
θ	0°		12°



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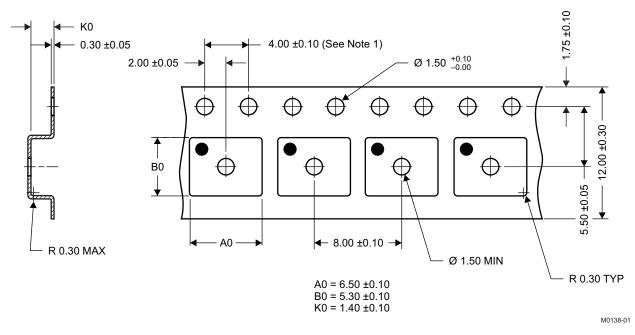
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DIM	MILLIM	IETERS	INC	HES
DIN	MIN	MAX	MIN	MAX
F1	6.205	6.305	0.244	0.248
F2	4.46	4.56	0.176	0.18
F3	4.46	4.56	0.176	0.18
F4	0.65	0.7	0.026	0.028
F5	0.62	0.67	0.024	0.026
F6	0.63	0.68	0.025	0.027
F7	0.7	0.8	0.028	0.031
F8	0.65	0.7	0.026	0.028
F9	0.62	0.67	0.024	0.026
F10	4.9	5	0.193	0.197
F11	4.46	4.56	0.176	0.18

For recommended circuit layout for PCB designs, see application note SLPA005 – Reducing Ringing Through PCB Layout Techniques.

Q5A Tape and Reel Information



Notes:

- 1. 10-sprocket hole-pitch cumulative tolerance ±0.2
- 2. Camber not to exceed 1mm in 100mm, noncumulative over 250mm
- 3. Material: black static-dissipative polystyrene
- 4. All dimensions are in mm (unless otherwise specified)
- 5. A0 and B0 measured on a plane 0.3mm above the bottom of the pocket



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PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/ Ball Finish	MSL Peak Temp ⁽³⁾	Samples (Requires Login)
CSD18504Q5A	ACTIVE	SON	DQJ	8	2500	Pb-Free (RoHS Exempt)	CU SN	Level-1-260C-UNLIM	

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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